



OCXO Part No: 0S560-1005-018

Issue 2; 6th May 2022

Features

- Temperature stability ±5ppb
- Low phase noise
- Frequency 10MHz
- Low pre-aged options available
- The flexible nature of the design means that variations to suit almost any application can be developed to meet individual customer requirements



- Temperature stability: ±5ppb over (0 to +50)°C
- Output: Sinewave 7dBm nominal
 Voltage: 12.0V
 Warm up current: 220mA
 Quiescent current: 120mA



F0₀+10Hz -128 dBc/Hz
 F0₀+100Hz -145 dBc/Hz
 F0₀+1KHz -155 dBc/Hz
 F0₀+10KHz -160 dBc/Hz
 F0₀+100KHz -168 dBc/Hz

Voltage / Load change

- ±5% supply voltage change: ±2ppb
- ±10% load change: ±10ppb

Ageing

After 30 days continuous operation:

- Per day: ±0.1ppb max.
- Per year: ±50ppb max.
- Warm up time: 5 minutes to within 0.1 ppm

Voltage Trim

- ±0.5ppm minimum
- Trim impedance 50KΩ

Reference Options

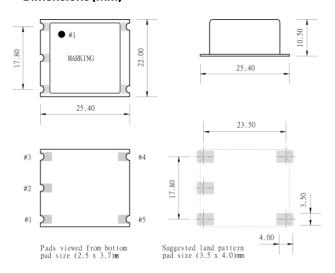
■ 4.5V

Environmental

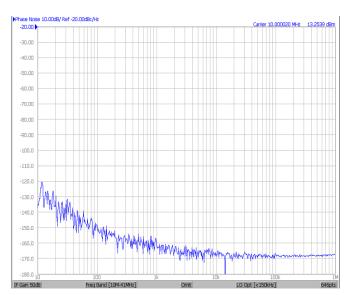
- Electrostatic-Sensitive Device (ESD)
- Storage Temperature Range: (-40 to +125)°C
- Mechanical shock: MIL standard 202, method 213, condition J
- Thermal shock: MIL standard 202, method 107, condition A



Dimensions (mm)



Phase Noise Plot



Europe & Asia : +44 1506 439 222 Email: sales@rfx.co.uk Web: www.rfx.co.uk

Americas: +1 289 481 2019 Email: sales@laptech.com Page: 1 of 2





- Vibration: MIL standard 202, method 204, condition B
- Solderability: 5 seconds maximum at 230°C
- 3 seconds maximum at 350°C

Compliance

- RoHS Status (2011/65/EU) Compliant
- **REACH Status Compliant**

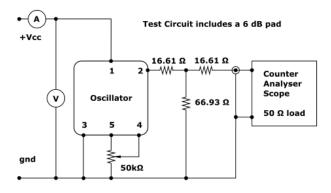
Packaging

■ Pack Style: Bulk

Ordering Information

- Unique customer part number and custom specification issued with each application
- OCXO Part No: 0S560-1005-018
- Frequency: 10MHz

Test Circuit - Sinewave



Europe & Asia: +44 1506 439 222 Email: sales@rfx.co.uk Web: www.rfx.co.uk Page: 2 of 2

Americas: +1 289 481 2019 Email: sales@laptech.com